



Software Verification and Validation for Embedded Systems— Volume 2

Guest Editor:

Prof. Dr. Byoungju Choi

Department of Computer Science
and Engineering, EWHA Womans
University, Seoul 03760, Korea

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Message from the Guest Editor

Dear Colleagues,
Embedded systems are electronically controlled devices where software and hardware are tightly coupled. The use of machine learning to create anomaly detectors is growing rapidly at the moment. Embedded systems often have unique characteristics that should be reflected in the verification and validation (V&V) plan. In this Special Issue, we are particularly interested in V&V at the software level for embedded systems.

- Methodologies for verification and validation of embedded software
- Techniques for testing of embedded software
- Tools and environment for automated and semi-automated embedded software testing
- Model-based testing
- Software test requirements
- Software test architecture
- Static vs. dynamic testing
- Performance, robustness, usability, and security testing
- Software fault injection
- Embedded real time software testing and runtime error handling
- Fault localization and debugging
- Application of machine learning to anomaly detection for embedded systems
- Empirical studies and experience reports





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Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

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Electronics Editorial Office
MDPI, Grosspeteranlage 5
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